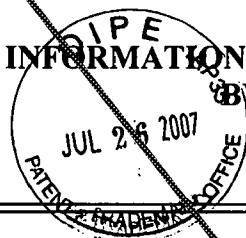


**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**



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| Attorney Docket Number | 1011-54375-01 |
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| First Named Inventor | Rajski |
| Art Unit | 2133 |
| Examiner Name | Phung M. Chung |

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

| Examiner's Initials* | Cite No. (optional) | Number | Publication Date | Name of Applicant or Patentee |
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FOREIGN PATENT DOCUMENTS

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